

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
212881US2SERIAL NO.  
NEW APPLICATION

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Eiji YOSHIDA

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GROUP



## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA					
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					
	AM					
	AN					

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
	AO				
	AP				
	AQ				
	AR				
	AS				
	AT				
	AU				
	AV				

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	Mario PANICCIA, et al., "NOVEL OPTICAL PROBING TECHNIQUE FOR FLIP CHIP PACKAGED MICROPROCESSORS", INTERNATIONAL TEST CONFERENCE 1998, IEEE, pp 740-747
	AX	T.M. EILES, et al., "OPTICAL INTERFEROMETRIC PROBING OF ADVANCED MICROPROCESSORS", INTERNATIONAL TEST CONFERENCE 2000, 5 pages
	AY	
	AZ	

Examiner **J. MONDT**Date Considered **May 9 '02.**

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U.S. PTO  
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